

Application/Control No.	Applicant(s)/Patent under Reexamination
10/509,802	HAYASHI ET AL.
Examiner	Art Unit
Mark L. Berch	1624

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
544/264 plus text term	3/30/2007	MLB	
CAS Online	3/30/2007	MLB	